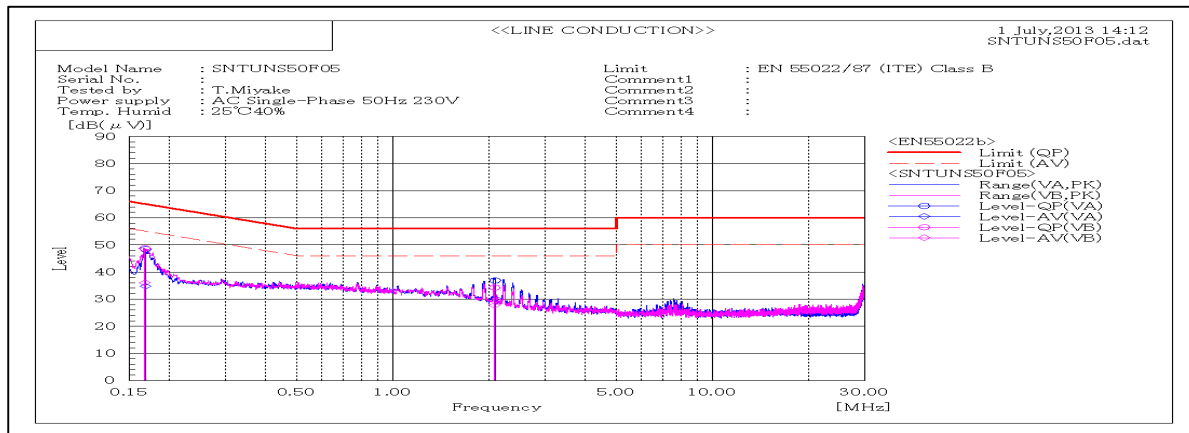
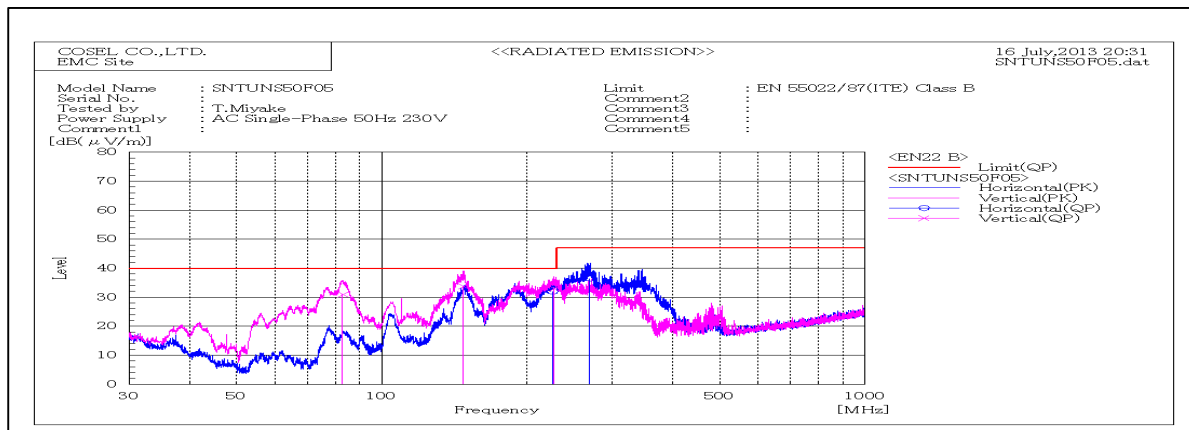


DATA SHEET		Date	19-Jul-13
Model	SNTUNS50F05	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake



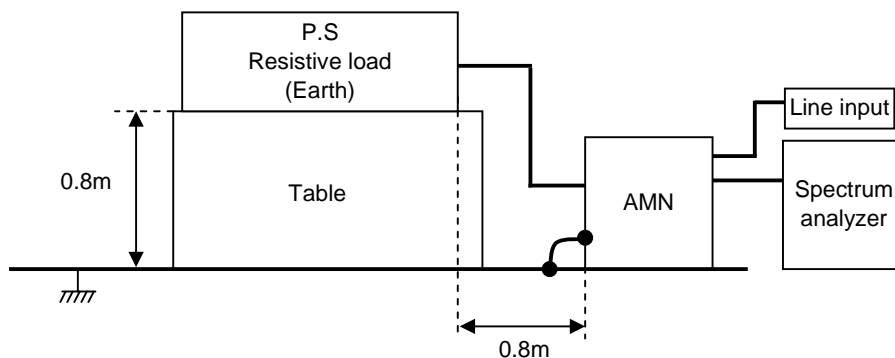
Frequency MHz	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
		QP	AV		QP	AV	QP	AV	QP	AV		
0.16754	VB	28.5	15.9	20.2	48.7	36.1	65.1	55.1	16.4	19	Pass	
0.16839	VA	28.2	14.6	20.2	48.4	34.8	65	55	16.6	20.2	Pass	
2.08216	VB	14.2	7.6	20.1	34.3	27.7	56	46	21.7	18.3	Pass	
2.09035	VA	16.8	10	20.1	36.9	30.1	56	46	19.1	15.9	Pass	



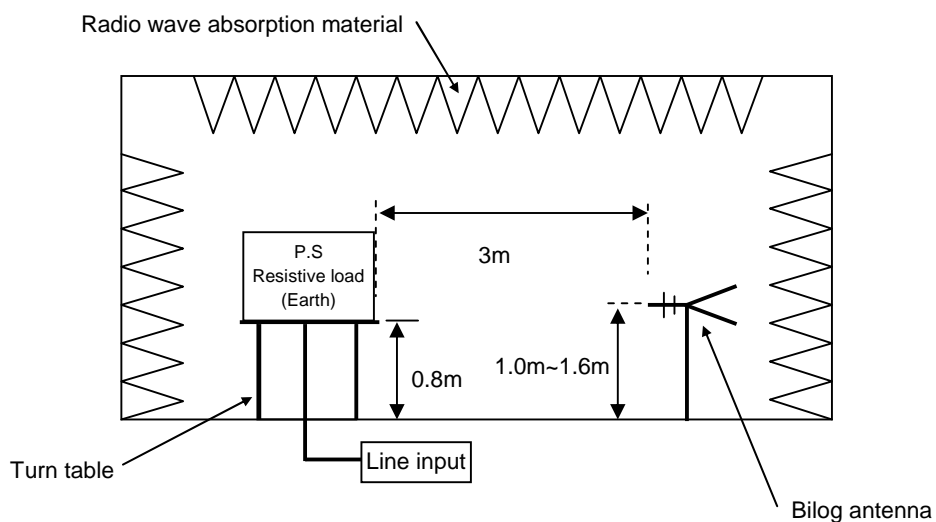
Frequency MHz	Polarization	Stability	Reading dB(μV)	Space Loss dB	Level dB(mW)	Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP		QP	QP	QP				
82.886	V	Stable	51.6	-20.7	30.9	40	9.1	Pass	118	31	
147.507	V	Stable	51.6	-17.8	33.8	40	6.2	Pass	123	270	
225.813	H	Stable	51.7	-19.7	32	40	8	Pass	113	93	
227.037	V	Stable	48	-15	33	40	7	Pass	118	148	
269.481	H	Stable	54.6	-18.1	36.5	47	10.5	Pass	113	258	

DATA SHEET		Date	19-Jul-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake

1. Line conduction



2. Radiated emission

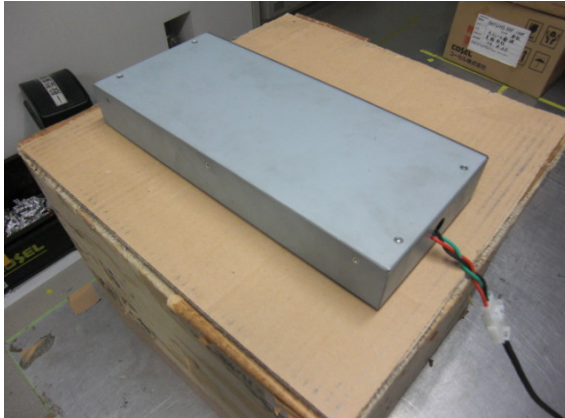


Test:EMI

Model Name: SNTUNS50F Series

○ Photographs of Test Set-Up

LINE CONDUCTION

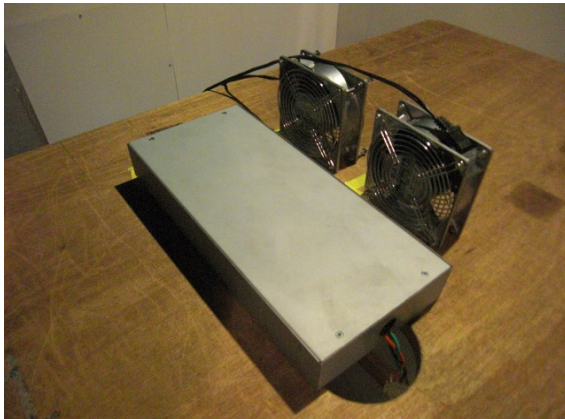


(A) Outside of a case

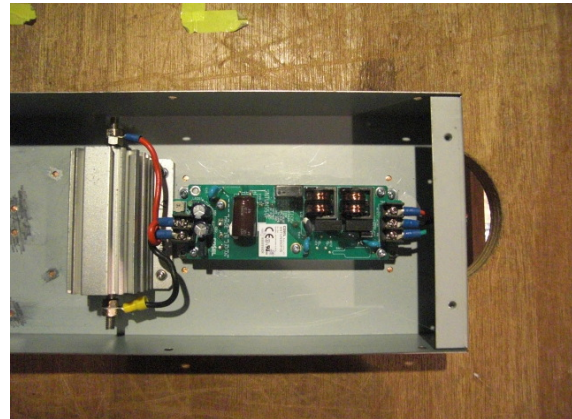


(B) Inside of a case

RADIATED EMISSION



(C) Outside of a case



(D) Inside of a case